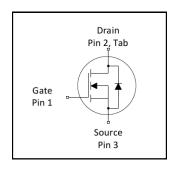
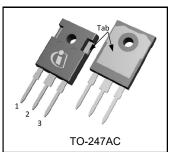


V _{DSS}	150V
R _{DS(on)} typ.	12m Ω
max.	15.5m Ω
I _D	78A





Applications

- Motion Control Applications
- High Efficiency Synchronous Rectification in SMPS
- Uninterruptible Power Supply
- Hard Switched and High Frequency Circuits

Benefits

- Low R_{DSON} Reduces Losses
- Low Gate Charge Improves the Switching Performance
- Improved Diode Recovery Improves Switching & EMI Performance
- 30V Gate Voltage Rating Improves Robustness
- Fully Characterized Avalanche SOA

Base Part Number	Package Type	Standard	Orderable Part Number	
		Form	Quantity	
IRFP4321PbF	TO-247AC	Tube	25	IRFP4321PbF

Absolute Maximum Ratings

Symbol	Parameter	Max.	Units	
I _D @ T _C = 25°C	Continuous Drain Current, V _{GS} @ 10V	78①		
I _D @ T _C = 100°C	Continuous Drain Current, V _{GS} @ 10V	55	Α	
I _{DM}	Pulsed Drain Current ②	330		
P _D @T _C = 25°C	Maximum Power Dissipation	310	W	
	Linear Derating Factor	2.0	W/°C	
V_{GS}	Gate-to-Source Voltage	± 30	V	
E _{AS (Thermally limited)} Single Pulse Avalanche Energy ③		210	mJ	
T _J Operating Junction and		55 to 1 175		
T _{STG}	Storage Temperature Range	-55 to + 175		
	Soldering Temperature, for 10 seconds (1.6mm from case)	300	°C	
	Mounting torque, 6-32 or M3 screw	10lbf-in (1.1N-m)		

Thermal Resistance

Symbol	Parameter	Тур.	Max.	Units
$R_{ hetaJC}$	Junction-to-Case ⑤		0.49	
$R_{ heta CS}$	Case-to-Sink, Flat Greased Surface	0.24		°C/W
$R_{ hetaJA}$	Junction-to-Ambient⑤		40	



Static @ $T_J = 25^{\circ}C$ (unless otherwise specified)

Symbol	Parameter	Min.	Тур.	Max.	Units	Conditions
	Drain-to-Source Breakdown Voltage	150			V	$V_{GS} = 0V, I_D = 250\mu A$
$\Delta V_{(BR)DSS}/\Delta T_J$	Breakdown Voltage Temp. Coefficient		150		mV/°C	Reference to 25°C, I _D = 1mA@
	Static Drain-to-Source On-Resistance		12	15.5	mΩ	V _{GS} = 10V, I _D =33A ④
$V_{GS(th)}$	Gate Threshold Voltage	3.0		5.0	V	$V_{DS} = V_{GS}$, $I_D = 250\mu A$
ı	Drain-to-Source Leakage Current			20	μΑ	$V_{DS} = 150V, V_{GS} = 0V$
I _{DSS}	Dialii-to-Source Leakage Current			1.0	mA	$V_{DS} = 150V, V_{GS} = 0V, T_{J} = 125^{\circ}C$
	Gate-to-Source Forward Leakage			100	nA	$V_{GS} = 20V$
I _{GSS}	Gate-to-Source Reverse Leakage			-100	IIA	$V_{GS} = -20V$
R_G	Internal Gate Resistance		0.8		Ω	

Dynamic @ T_J = 25°C (unless otherwise specified)

Symbol	Parameter	Min.	Тур.	Max.	Units	Conditions
gfs	Forward Transconductance	130			S	$V_{DS} = 25V, I_{D} = 50A$
Q_g	Total Gate Charge		71	110		$I_D = 50A$
Q_{gs}	Gate-to-Source Charge		24		nC	$V_{DS} = 75V$
Q_{gd}	Gate-to-Drain ("Miller") Charge		21			V _{GS} = 10V ④
$t_{d(on)}$	Turn-On Delay Time		18			$V_{DD} = 75V$
t _r	Rise Time		60		20	$I_D = 50A$
$t_{d(off)}$	Turn-Off Delay Time		25		ns	$R_G = 2.5\Omega$
t _f	Fall Time		35			V _{GS} = 10V ④
C _{iss}	Input Capacitance		4460			$V_{GS} = 0V$
C _{oss}	Output Capacitance		390		pF	$V_{DS} = 25V$
C _{rss}	Reverse Transfer Capacitance		82			f = 1.0 MHz

Diode Characteristics

Symbol	Parameter	Min.	Тур.	Max.	Units	Conditions
Is	Continuous Source Current			70①	۸	MOSFET symbol
	(Body Diode)			78①) A	showing the
I _{SM}	Pulsed Source Current			220	۸	integral reverse
	(Body Diode) ②		330 /	330 A	p-n junction diode.	
V_{SD}	Diode Forward Voltage			1.3	V	$T_J = 25^{\circ}C$, $I_S = 50$ A, $V_{GS} = 0V$ ④
t _{rr}	Reverse Recovery Time		89	130	ns	I _F = 50A
Q_{rr}	Reverse Recovery Charge		300	450	nC	V _R = 128V
I _{RRM}	Reverse Recovery Current		6.5		Α	di/dt = 100A/µs ④
t _{on}	Forward Turn-On Time	Intrinsi	c turn-o	n time is	s negligib	le (turn-on is dominated by L _S +L _D)

Notes:

- ① Calculated continuous current based on maximum allowable junction temperature. Package limitation current is 75A
- ② Repetitive rating; pulse width limited by max. Junction temperature.
- \odot Limited by T_{Jmax} , starting $T_J = 25$ °C, L = 0.17mH, $R_G = 25\Omega$, $I_{AS} = 50$ A, $V_{GS} = 10$ V. Part not recommended for use above this value.
- ⊕ Pulse width ≤ 400µs; duty cycle ≤ 2%.
- $\$ R_{θ} is measured at T_J approximately 90°C.



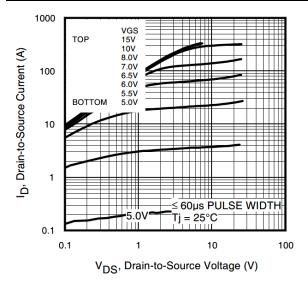


Fig 1. Typical Output Characteristics

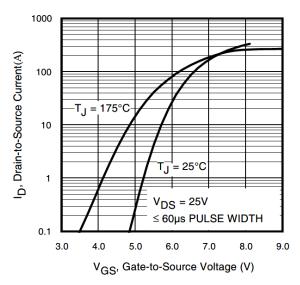


Fig 3. Typical Transfer Characteristics

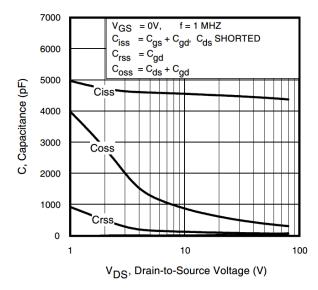


Fig 5. Typical Capacitance vs. Drain-to-Source Voltage

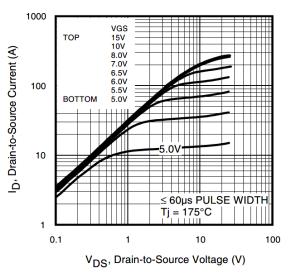


Fig 2. Typical Output Characteristics

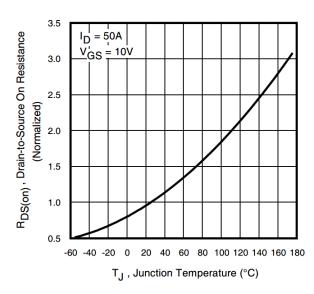


Fig 4. Normalized On-Resistance vs. Temperature

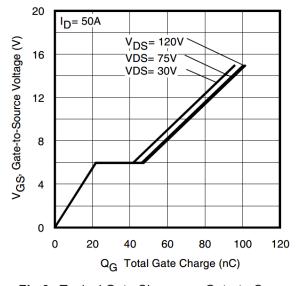


Fig 6. Typical Gate Charge vs. Gate-to-Source Voltage



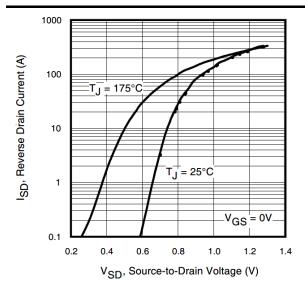


Fig 7. Typical Source-to-Drain Diode Forward Voltage

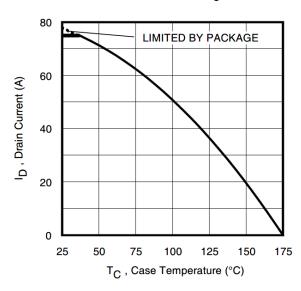


Fig 9. Maximum Drain Current vs. Case Temperature

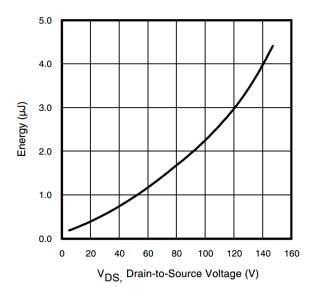


Fig 11. Typical Coss Stored Energy

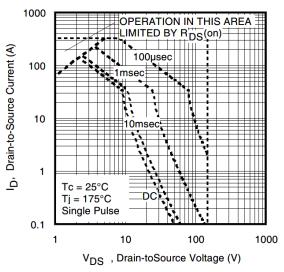


Fig 8. Maximum Safe Operating Area

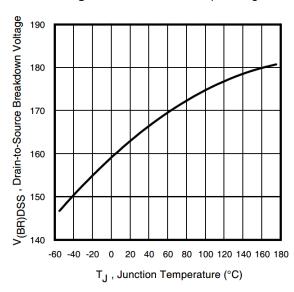


Fig 10. Drain-to-Source Breakdown Voltage

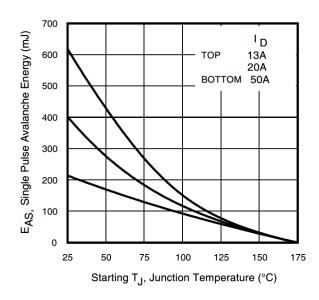


Fig 12. Maximum Avalanche Energy vs. Drain Current



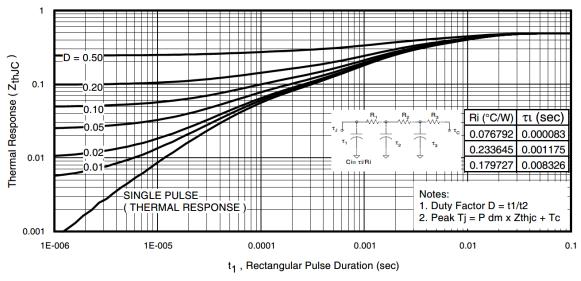


Fig 13. Maximum Effective Transient Thermal Impedance, Junction-to-Case

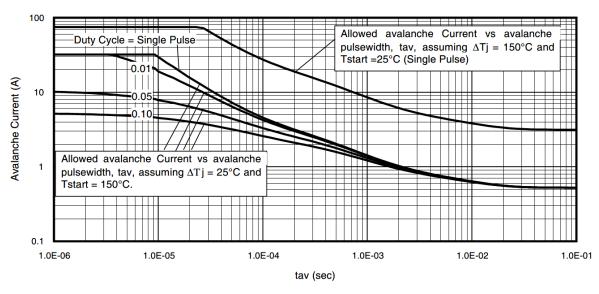


Fig 14. Typical Avalanche Current vs. Pulsewidth

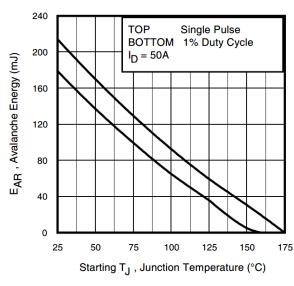


Fig 15. Maximum Avalanche Energy vs. Temperature

Notes on Repetitive Avalanche Curves, Figures 14, 15: (For further info, see AN-1005 at www.irf.com)

(For further info, see AN-1005 at www.irf.com)

1. Avalanche failures assumption:

Purely a thermal phenomenon and failure occurs at a temperature far in excess of Timax. This is validated for every part type.

Safe operation in Avalanche is allowed as long as Tjmax is not exceeded.

Equation below based on circuit and waveforms shown in Figures 16a, 16b.

4. P_{D (ave)} = Average power dissipation per single avalanche pulse.

5. BV = Rated breakdown voltage (1.3 factor accounts for voltage increase during avalanche).

6. I_{av} = Allowable avalanche current.

7. ΔT = Allowable rise in junction temperature, not to exceed Tjmax (assumed as 25°C in Figure 14, 15). t_{av} = Average time in avalanche.

t_{av} = Average time in avalanche.

D = Duty cycle in avalanche = tav ·f

 $Z_{thJC}(D, t_{av})$ = Transient thermal resistance, see Figures 13)

$$\begin{split} P_{D \; (ave)} &= 1/2 \; (\; 1.3 \cdot BV \cdot I_{av}) = \Delta T / \; Z_{thJC} \\ I_{av} &= 2\Delta T / \; [1.3 \cdot BV \cdot Z_{th}] \\ E_{AS \; (AR)} &= P_{D \; (ave)} \cdot t_{av} \end{split}$$



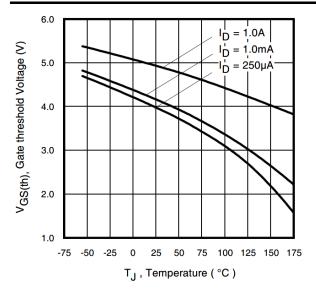


Fig. 16 Threshold Voltage vs. Temperature

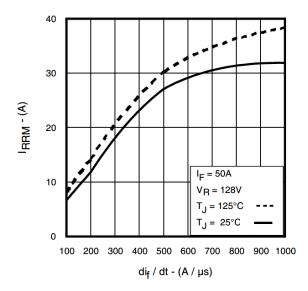


Fig 18. Typical Recovery Current vs. di_f/dt

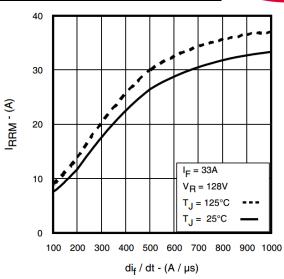


Fig. 17 Typical Recovery Current vs. di_f/dt

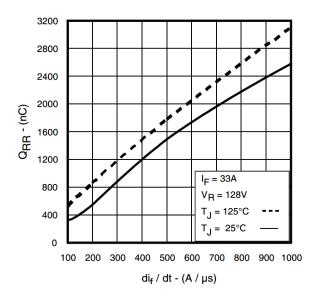


Fig 19. Typical Stored Charge vs. di_f/dt

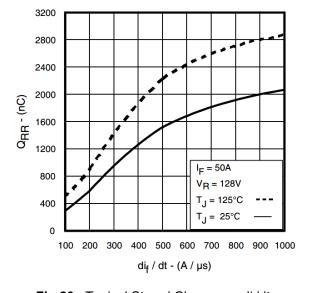
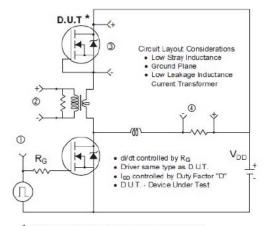


Fig 20. Typical Stored Charge vs. di_f/dt





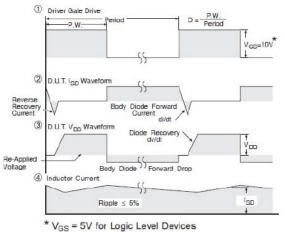


Fig 21. Peak Diode Recovery dv/dt Test Circuit for N-Channel HEXFET® Power MOSFETs

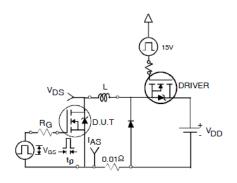


Fig 22a. Unclamped Inductive Test Circuit

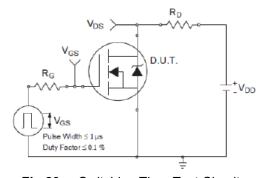


Fig 23a. Switching Time Test Circuit

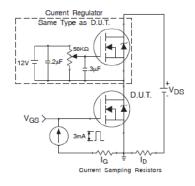


Fig 24a. Gate Charge Test Circuit

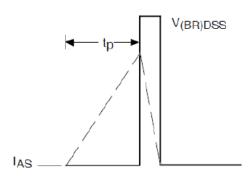


Fig 22b. Unclamped Inductive Waveforms

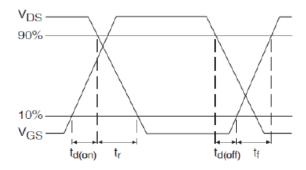


Fig 23b. Switching Time Waveforms

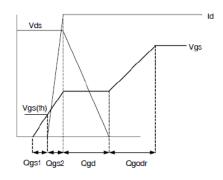
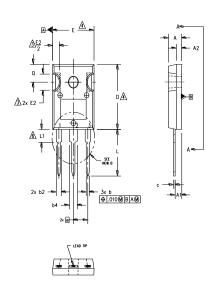


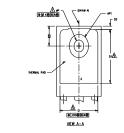
Fig 24b. Gate Charge Waveform

^{*} Reverse Polarity of D.U.T for P-Channel

infineon

TO-247AC Package Outline (Dimensions are









TO-247AC Part Marking Information

NOTES:

1. DIMENSIONING AND TOLERANCING AS PER ASME Y14.5M 1994.

2. DIMENSIONS ARE SHOWN IN INCHES.

CONTOUR OF SLOT OPTIONAL.

, DIMENSION D & E DO NOT INCLUDE MOLD FLASH. MOLD FLASH SHALL NOT EXCEED .005" (0.127)
PER SIDE. THESE DIMENSIONS ARE MEASURED AT THE OUTERMOST EXTREMES OF THE PLASTIC BODY.

 $\sqrt{5}$ thermal pad contour optional within dimensions D1 & E1.

LEAD FINISH UNCONTROLLED IN L1.

OP TO HAVE A MAXIMUM DRAFT ANGLE OF 1.5 * TO THE TOP OF THE PART WITH A MAXIMUM HOLE DIAMETER OF .154 INCH.

8. OUTLINE CONFORMS TO JEDEC OUTLINE TO-247AC .

SYMBOL	INC	HES	MILLIM	ETERS	
	MIN.	MAX.	MIN.	MAX.	NOTES
A	.183	.209	4.65	5.31	
A1	.087	.102	2.21	2.59	
A2	.059	.098	1.50	2.49	
b	.039	.055	0.99	1.40	
b1	.039	.053	0.99	1.35	
b2	.065	.094	1.65	2.39	
b3	.065	.092	1.65	2.34	
b4	.102	.135	2.59	3.43	
b5	.102	.133	2.59	3.38	
С	.015	.035	0.38	0.89	
c1	.015	.033	0.38	0.84	
D	.776	.815	19.71	20.70	4
D1	.515	-	13.08	-	5
D2	.020	.053	0.51	1.35	
E	.602	.625	15.29	15.87	4
E1	.530	-	13.46	-	
E2	.178	.216	4.52	5.49	
e	.215	BSC	5.46	BSC	
Øk	.0	10	0.	25	
L	.559	.634	14.20	16.10	
L1	.146	.169	3.71	4.29]
øΡ	.140	.144	3.56	3.66	
øP1	-	.291	-	7.39	
Q	.209	.224	5.31	5.69	
S	.217	BSC	5.51	BSC	

LEAD ASSIGNMENTS

<u>HEXFET</u>

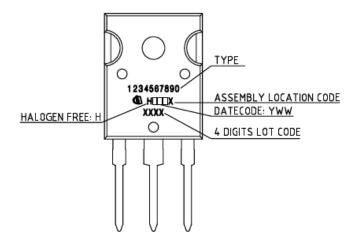
- 1.- GATE
- 2.- DRAIN 3.- SOURCE
- 4. DRAIN

IGBTs, CoPACK

- 1.- GATE
- 2.- COLLECTOR 3.- EMITTER
- 4.- COLLECTOR

DIODES

- 1.- ANODE/OPEN
- 2.- CATHODE
- 3.- ANODE



TO-247AC package is not recommended for Surface Mount Application.



Revision History

Date	Rev.	Comments
11/25/2024	2.1	 Update datasheet to Infineon format Updated Part marking –page 8 Added disclaimer on last page.

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